


<b>Search Notes</b>  	<b>Application/Control No.</b>  10643422	<b>Applicant(s)/Patent Under Reexamination</b>  TANAKA ET AL.
	<b>Examiner</b>  Kim-Kwok CHU	<b>Art Unit</b>  2627

SEARCHED			
Class	Subclass	Date	Examiner
369	47.16	11/7/2008	kc
369	59.26	11/7/2008	kc
84	631	11/7/2008	kc
84	600	11/7/2008	kc
84	632	11/7/2008	kc
386	52	11/7/2008	kc
386	46	11/7/2008	kc

SEARCH NOTES		
Search Notes	Date	Examiner
East Search Updated	11/7/2008	kc

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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